

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|-------|--|--|------------------|---------|------------------|
| L2 | 27182 | ((substrate wafer) near4 (temperature heat\$3)) with (measur\$5 or sens\$3 or detect\$3 or determin\$5) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/07/13 21:27 |
| L6 | 85192 | ((shape cross-section\$3) size location position disposed) near3 (beam light radiation illumination) with (correct\$3 adjust\$4 compensat\$3 chang\$3) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/07/13 21:29 |
| L8 | 4264 | (substrate wafer) with ((dimension\$3 near response) expan\$4 deform\$5) with (correct\$3 or adjust\$4 or compensat\$3) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/07/13 21:29 |
| L9 | 10859 | ((substrate wafer) with (temperature heat\$3)) with ((dimension\$3 near response) expan\$4 deform\$5) with (calculat\$3 determin\$5 predict\$3 model\$3 coefficient) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/07/13 21:35 |
| L11 | 14 | 2 and 6 and 8 and 9 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/07/13 21:33 |
| L12 | 1 | (2 and 6 and 8 and 9).clm. | US-PGPUB | OR | ON | 2007/07/13 21:33 |
| L13 | 6426 | (substrate wafer) with ((dimension\$3 near response) expan\$4 deform\$5 (spatial near distribution)) with (measur\$5 sens\$3 detect\$3 determin\$5) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/07/13 21:37 |

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|-----|-----|---|--|----|----|------------------|
| L14 | 243 | ((alignment near (feature or mark or pattern)) or (fiducial near (feature mark pattern))) with ((dimension\$3 near response) expan\$4 deform\$5 (spatial near distribution)) with (measur\$5 sens\$3 detect\$3 determin\$5) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/07/13 21:39 |
| L15 | 160 | ((alignment near (feature or mark or pattern)) or (fiducial near (feature mark pattern))) with (measur\$5 sens\$3 detect\$3 determin\$5) with (temperature or heat\$3) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/07/13 21:39 |
| L16 | 15 | 13 and 14 and 15 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/07/13 21:40 |
| L17 | 1 | (13 and 14 and 15).clm. | US-PGPUB | OR | ON | 2007/07/13 21:40 |


 7/13/07